

1ST DRD3 WEEK RESULTS AND PERSPECTIVES OF THE MONOPIX2 DEPLETED MONOLITHIC ACTIVE PIXEL SENSORS

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Brief Overview of Our CMOS Developments

- Started CMOS development in 2012-2013 with simple prototypes from multiple foundries
- 2016/2017: Submission of two fully monolithic large-scale designs utilizing two different technologies (LFoundry and TowerSemi) → the Monopix1 chips
 - TJ development line based on ALPIDE, in parallel to MALTA developments
 - Second iteration of both chips received in 2021
- Design and characterization were collaborative efforts driven by multiple institutes!
 - Bonn, CPPM Marseille, IRFU CEA Saclay, CERN (only TJ developments), initially also KIT

CCPD-LF (2014)





LF-Monopix1 (2017)



MALTA / TJ-Monopix1 (2018)



miniMALTA (2018)



P. Freeman, 2019

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LF-Monopix Development Line

- Large collection electrode design:
 - Large sensor capacitance O(100 fF)
 - Short drift distance
 - Uniform electric field across pixel area
- \rightarrow Radiation hard
- 150 nm LFoundry CMOS technology
- Substrate resistivity >2 kΩcm
- Latest DMAPS LF-Monopix2:
 - Large scale 1x2 cm² chip with 150x50 μm² pixel pitch
 - 6-bit ToT information, 4-bit in-pixel threshold tuning
 - Fast column drain readout architecture (FE-I3 like)





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LF-Monopix2: Laboratory Test

- Breakdown voltage around 460 V before irradiation
 - No breakdown up to 300 V after irradiation
 - Facilitates high radiation tolerance
 - Increase in leakage current ca. 6 μA/cm² per 1 x 10¹⁵ neq/cm² irradiation step (@ 100 V)
- Typical operational threshold of around 2.0 ± 0.1 ke[−]
 - Constant across all available fluences
 - Charge MPV of MIPs at full depletion roughly 6 ke⁻ (for 100 μm thickness)
- Roughly 40 % increase in ENC per irradiation step





- Very high and homogeneous hit-detection efficiency >99 % for all fluences at full depletion
 - Full depletion reached around 150 V after 2 x 10¹⁵ neq/cm² of NIEL fluence
 - All samples irradiated with protons, annealed for 80 min @ 60 °C
- Mean in-time efficiency within 25 ns of >98 % after irradiation to 2 x 10¹⁵ neq/cm²





LF-Monopix2: TID Irradiation

- Irradiated up to 100 Mrad total ionizing dose, fully responsive throughout the entire campaign
 - Expected peak in VDDD current around 1 10 Mrad, drop in VDDA current towards high doses
 - No change or drop in gain observable throughout irradiation
- Typical operational threshold and threshold dispersion reachable after 100 Mrad and annealing





TJ-Monopix Development Line

- Small collection electrode design:
 - Small sensor capacitance (<5 fF)
 - Longer drift distances
 - Potentially regions with low electric field
- \rightarrow Low power and low noise operation
- 180 nm TowerSemi CMOS technology
- Substrate resistivity >1 kΩcm
- Latest DMAPS TJ-Monopix2:
 - Large scale $2x2 \text{ cm}^2$ chip with $33x33 \mu \text{m}^2$ pixel pitch
 - 7-bit ToT information, 3-bit in-pixel threshold tuning
 - Fast column drain readout architecture (FE-I3 like)







TJ-Monopix2: Laboratory Tests

- Typical operating conditions around 200 250 e⁻ threshold and 6 e⁻ ENC
 - Sufficient for excellent hit-detection efficiency (MIP charge MPV >2500 e⁻)
- Front-end <100 ps time resolution for MIP charge regime
 - Total time resolution including sensor contribution <1.5 ns





- Very uniform hit-detection efficiency >99.9 % before irradiation
- 99.68 % of hits within a 25 ns window, still 99 % within 10 ns window
- Achievable spatial resolution <9 μm with clustering









TJ-Monopix2: TID Irradiation

- Irradiated up to 100 Mrad total ionizing dose, fully responsive throughout the entire campaign
 - Peak in current around 1 10 Mrad, highest relative increase for VDDD
 - Periphery biggest absolute contributor to power consumption
 - Still <20 e⁻ ENC after 100 Mrad before annealing
- Typical operational threshold still reachable after 100 Mrad and annealing





LF-Monopix2:

- Excellent radiation hardness without significant performance degradation up to 2 x 10¹⁵ neq/cm²
 NIEL fluence and 100 Mrad TID
 - Further irradiation up to 5 x10¹⁵ neq/cm² NIEL fluence planned

TJ-Monopix2:

- Very low noise and low threshold operation with excellent spatial resolution
- >99 % hit-detection efficiency and very high in-time ratio >99 % within 25 ns
- Fully functional after 100 Mrad TID
 - Characterization of irradiated samples up to 1.5 x 10¹⁵ neq/cm² NIEL fluence ongoing

Perspectives:

• New DMAPS based on TJ-Monopix2 under development for Belle II VXD upgrade -*talk by M. Babeluk*



Thank you for your attention!

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Backup